

**Search Notes**

Application/Control No.

10/576,634

Examiner

BIN SHEN

Applicant(s)/Patent under  
Reexamination

SANDERS ET AL.

Art Unit

1657

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR